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EAST SEARCH

6/24/04

L#	Hits	Search String
L2	26	6,044,209.pn. or 5,859,776.pn. or 5,883,808.pn. or 5,764,528.pn. or 5,838,581.pn. or 5,446,6 USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB
L3	121	((integrated or digital) adj circuit\$1) with noise with model\$3
L4	8878	((integrated or digital) adj circuit\$1) with noise
L4	314	4 and (noise with model\$3)
L5	47	5 and ((“resistor capacitor” or RC) with circuit\$1)
L6	31	4 and ((“resistor capacitor” or RC) with circuit\$1 with type\$1)
L7	31	5 and (victim\$1 with aggressor\$1)
L8	26	5 and (coupling with aggressor\$1)
L9	32	5 and (coupling with victim)
L10	90	5 and (noise with (peak or width))
L11	39	5 and (noise with width)
L12	106	5 and (“transition time” or “elmore delay” or “threshold voltage”)
L13	69	5 and (coupling with (resistance or capacitance or location))
L14	36	13 and 14
L15	39	11 and 12
L16	39	5 and (“crosstalk noise”)
L17	18	18 and (sink and source)
L18	0	18 and (receiver and transmitter)
L19	0	5 and ((sink and source) or (receiver and transmitter))
L20	0	5 and (lumped with capacitance\$1 with weight\$2)
L21	70	5 and (lumped with capacitance\$1)
L22	18	24 and (path or branch)
L23	0	5 and ((“resistor capacitor” or RC) with circuit\$1) or (victim\$1 with aggressors\$1) or (coupling
L24	18	5 and ((“resistor capacitor” or RC) with circuit\$1 with pi)
L25	16	5 and (“RC delay”)
L26	172	5 and (capacitance\$1 with weight\$2)
L27	5	26 and (noise with peak with threshold)
L28	6	26 and (noise with “pulse width”)
L29	1	4 and (noise with “pulse width”)
L30	8	31 and “elmore delay”
L31	158	4 and “pi model”
L32	0	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB
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Jason Cong

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<u><b>Results of search set L24:(processors\$1 or "processing unit") with ((estimat\$3 or determin\$5 or calculat\$3) near2 electromagnetic)</b></u>						
Document Kind	Codes Title	Code Title	Issue Date	Current OR	Abstract	
US 20040103386 A1	Noise analysis for an integrated circuit model		20040527 716/13			
US 20040103381 A1	Semiconductor integrated circuit designing apparatus, semiconductor integrated circuit design		20040527 716/5			
US 20040087285 A1	VCO gain tracking for modulation gain setting calibration		20040506 455/126			
US 20040051511 A1	Method for delta-I noise reduction		20040318 323/283			
US 20040024554 A1	Method and apparatus for calibrating parameters to be used in a digital circuit simulation		20040205 702/107			
US 20040021599 A1	System and method for detecting an intruder using impulse radio technology		20040205 342/28			
US 20040019864 A1	METHOD AND APPARATUS FOR ANALYZING INDUCTIVE EFFECTS IN A CIRCUIT LAYC		20040129 716/6			
US 20040017224 A1	Integrated circuit and sensor for imaging		20040129 327/51			
US 20040013276 A1	Analog audio signal enhancement system using a noise suppression algorithm		20040122 381/94.3			
US 20030233622 A1	Method and apparatus for an asynchronous pulse logic circuit		20031218 716/1			
US 20030227032 A1	Wiring design method of integrated circuit device, system thereof, and program product there		20031211 257/208			
US 20030210101 A1	MEMS-based, computer systems, clock generation and oscillator circuits and LC-tank appara		20031113 331/117FE			
US 20030177427 A1	Circuit modeling		20030918 714/741			
US 20030176982 A1	Manufacturing integrated circuits and testing on-die power supplies using distributed program		20030918 702/60			
US 20030169121 A1	Method and apparatus to attenuate power plane noise on a printed circuit board using high E:		20030911 333/12			
US 200301632277 A1	Method for simulating power supply noise in an on-chip temperature sensor		20030828 702/136			
US 20030159121 A1	Variable stage ratio buffer insertion for noise optimization in a logic network		20030821 716/8			
US 20030155966 A1	Low-power, low-noise CMOS amplifier		20030821 330/9			
US 20030154454 A1	Method and system for estimating jitter in a delay locked loop		20030814 716/6			
US 20030154453 A1	Optimization of loop bandwidth for a phase locked loop		20030814 716/5			
US 20030154447 A1	Method for optimizing loop bandwidth in delay locked loops		20030814 716/2			
US 20030154065 A1	Method for optimizing decoupling capacitor design in delay locked loops		20030814 703/14			
US 20030154064 A1	Decoupling capacitor method for a phase locked loop		20030814 703/14			
US 20030154048 A1	Method for decoupling capacitor optimization for a temperature sensor design		20030814 331/72			
US 20030151464 A1	Jitter estimation for a phase locked loop		20030814 331/74			
US 20030138111 A1	Noise-suppressing receiver		20030724 381/71.7			
US 20030137877 A1	Noise reduction technique for transistors and small devices utilizing an episodic agitation		20030724 365/185.19			
US 20030128071 A1	Variable transconductance variable gain amplifier utilizing a degenerated differential pair		20030710 330/254			
US 20030115563 A1	Method for estimating peak crosstalk noise		20030619 716/5			
US 20030100040 A1	Blood analyte monitoring through subcutaneous measurement		20030529 435/14			
US 20030079191 A1	Cell-based noise characterization and evaluation		20030424 716/4			
US 20030030497 A1	Integrated VCO having an improved tuning range over process and temperature variations		20030213 331/34			
US 20030021440 A1	Digital watermarking employing noise model		20030130 382/100			
US 20030011424 A1	Simultaneous switching noise minimization technique for power lines using dual layer power li		20030116 327/565			
US 20020194573 A1	Method for simulating noise on the input of a static gate and determining noise on the output		20021219 716/5			
US 20020193959 A1	System and method of determining the noise sensitivity characterization for an unknown circu		20021219 702/117			
US 20020183054 A1	Mobile system testing architecture		20021205 455/423			
US 20020174409 A1	System and method for analyzing power distribution using static timing analysis		20021121 716/6			
US 20020147956 A1	System and method of determining the noise sensitivity of an integrated circuit		20021121 716/5			
US 20020147956 A1	Method for modeling noise emitted by digital circuits		20021010 716/4			

US 20020147555 A1	Method and apparatus for analyzing a source current waveform in a semiconductor integrated circuit	20021010 70270
US 20020130807 A1	Electromagnetic disturbance analysis method and apparatus and semiconductor device manu	20021010 702/65
US 20020121994 A1	System and method for detecting an intruder using impulse radio technology	20020919 34/2/28
US 20020121994 A1	Delta-sigma modulator system and method	20020905 34/1/43
US 20020050861 A1	Variable transconductance variable gain amplifier utilizing a degenerated differential pair	20020502 330/254
US 20020047942 A1	Digital IF demodulator for video applications	20020425 348/731
US 20020024407 A1	Distributed constant type noise filter	20020228 333/184
US 20020022951 A1	Method, apparatus and computer program product for determination of noise in mixed signal :	20020221 703/16
US 20010041548 A1	Variable gain amplifier for low voltage applications	20011115 455/252.1
US 20010025139 A1	Multivariate cardiac monitor	20010927 600/301
US 6751744 B1	Method of integrated circuit design checking using progressive individual network analysis	20040615 713/401
US 6750515 B2	SCR devices in silicon-on-insulator CMOS process for on-chip ESD protection	20040615 257/357
US 6748339 B2	Method for simulating power supply noise in an on-chip temperature sensor	20040608 702/136
US 6747501 B2	Dual-triggered electrostatic discharge protection circuit	20040608 327/310
US 6744320 B2	Variable transconductance variable gain amplifier utilizing a degenerated differential pair	20040601 330/254
US 6737887 B2	Current mode signal interconnects and CMOS amplifier	20040518 326/86
US 6732339 B2	Cell-based noise characterization and evaluation	20040504 716/4
US 6732336 B2	Method and apparatus for an asynchronous pulse logic circuit	20040504 716/1
US 6732065 B1	Noise estimation for coupled RC interconnects in deep submicron integrated circuits	20040504 703/2
US 6723577 B1	Method of forming an optical fiber interconnect through a semiconductor wafer	20040420 438/31
US 6718530 B2	Method and apparatus for analyzing inductive effects in a circuit layout	20040406 716/6
US 6704680 B2	Method for decoupling capacitor optimization for a temperature sensor design	20040309 702/130
US 6693439 B1	Apparatus and methods for measuring noise in a device	20040217 324/613
US 6691291 B2	Method and system for estimating jitter in a delay locked loop	20040210 716/6
US 6690065 B2	Substrate-biased silicon diode for electrostatic discharge protection and fabrication method	20040210 257/355
US 6687881 B2	Method for optimizing loop bandwidth in delay locked loops	20040203 716/2
US 6684065 B2	Variable gain amplifier for low voltage applications	20040127 455/252.1
US 6675365 B2	Method and system for predicting worst-case capacitive and inductive switching vector	20040106 716/6
US 6675118 B2	System and method of determining the noise sensitivity characterization for an unknown circu	20040106 702/117
US 6671863 B2	Optimization of loop bandwidth for a phase locked loop	20031230 716/6
US 6665845 B1	System and method for topology based noise estimation of submicron integrated circuit design	20031216 716/5
US 6657566 B1	Conversion of a PWM signal into a UPWM signal	20031202 34/1/53
US 6653967 B2	Fully differential sampling circuit	20031125 34/1/172
US 6646523 B2	Distributed constant type noise filter	20031111 333/184
US 6633068 B2	Low-noise silicon controlled rectifier for electrostatic discharge protection	20031014 257/355
US 6617649 B2	Low substrate-noise electrostatic discharge protection circuits with bi-directional silicon diode:	20030909 257/355
US 6614384 B2	System and method for detecting an intruder using impulse radio technology	20030902 342/28
US 6611026 B2	Substrate-biased silicon diode for electrostatic discharge protection and fabrication method	20030826 257/355
US 6600243 B1	Battery pack and an information processing device in which the battery pack is detachable/att	20030729 307/150
US 6594805 B1	Integrated design system and method for reducing and avoiding crosstalk	20030715 716/5
US 6594630 B1	Voice-activated control for electrical device	20030715 704/256
US 6587815 B1	Windrowing scheme for analyzing noise from multiple sources	20030701 703/13
US 6586835 B1	Compact system module with built-in thermoelectric cooling	20030701 257/717

US 6579690 B1	Blood analyte monitoring through subcutaneous measurement	20030617 435/14
US 6576974 B1	Bipolar junction transistors for on-chip electrostatic discharge protection and methods thereof	20030610 257/499
US 6570248 B1	Structure and method for a high-performance electronic packaging assembly	20030527 257/724
US 6567773 B1	Use of static noise analysis for integrated circuits fabricated in a silicon-on-insulator process	20030520 703/14
US 6564355 B1	System and method for analyzing simultaneous switching noise	20030513 716/4
US 6556954 B1	Method and device for determining a fault in a technical system	20030429 702/185
US 6546529 B1	Method for performing coupling analysis	20030408 716/5
US 6539527 B2	System and method of determining the noise sensitivity of an integrated circuit	20030325 716/5
US 6536022 B1	Two pole coupling noise analysis model for submicron integrated circuit design verification	20030318 716/5
US 6526191 B1	Integrated circuits using optical fiber interconnects formed through a semiconductor wafer and	20030225 385/14
US 6523149 B1	Method and system to improve noise analysis performance of electrical circuits	20030218 716/4
US 6509796 B2	Variable transconductance variable gain amplifier utilizing a degenerated differential pair	20030121 330/254
US 6507935 B1	Method of analyzing crosstalk in a digital logic integrated circuit	20030114 716/5
US 6502223 B1	Method for simulating noise on the input of a static gate and determining noise on the output	20021231 716/5
US 6499131 B1	Method for verification of crosstalk noise in a CMOS design	20021224 716/5
US 6496370 B2	Structure and method for an electronic assembly	20021217 361/699
US 6493853 B1	Cell-based noise characterization and evaluation	20021210 716/5
US 6493395 B1	Multi-carrier transmission systems	20021210 375/261
US 6480998 B1	Iterative, noise-sensitive method of routing semiconductor nets using a delay noise threshold	20021112 716/13
US 6466629 B1	Multi-carrier transmission systems	20021015 375/316
US 6456649 B1	Multi-carrier transmission systems	20020924 375/222
US 6449753 B1	Hierarchical coupling noise analysis for submicron integrated circuit designs	20020910 716/5
US 6438174 B1	Multi-carrier transmission systems	20020820 375/261
US 6426680 B1	System and method for narrow band PLL tuning	20020730 331/34
US 6424034 B1	High performance packaging for microprocessors and DRAM chips which minimizes timing skew	20020723 257/723
US 6392296 B1	Silicon interposer with optical connections	20020521 257/698
US 6385565 B1	System and method for determining the desired decoupling components for power distribution	20020507 703/18
US 63778109 B1	Method of simulation for gate oxide integrity check on an entire IC	20020423 716/4
US 63633516 B1	Method for hierarchical parasitic extraction of a CMOS design	20020326 716/5
US 6363128 B1	Multi-carrier transmission systems	20020326 375/355
US 6281042 B1	Structure and method for a high performance electronic packaging assembly	20010828 438/108
US 6272465 B1	Monolithic PC audio circuit	20010807 704/258
US 6246774 B1	Waveable audio synthesizer with multiple volume components and two modes of stereo position	20010612 381/104
US 6219237 B1	Structure and method for an electronic assembly	20010417 361/699
US 6188344 B1	Signal processors	20010213 341/143
US 6177665 B1	High-speed logarithmic photo-detector	20010123 250/207
US 6150188 A	Integrated circuits using optical fiber interconnects formed through a semiconductor wafer and	20000121 438/31
US 6144217 A	Low switching noise logic circuit	20000107 326/27
US 6117182 A	Optimum buffer placement for noise avoidance	20000912 716/8
US 6104588 A	Low noise electrostatic discharge protection circuit for mixed signal CMOS integrated circuits	20000815 361/111
US 6090636 A	Integrated circuits using optical waveguide interconnects formed through a semiconductor wafer	20000718 438/31
US 6073259 A	Low cost CMOS tester with high channel density	20000606 714/724
US 6072947 A	Method of making an integrated circuit including noise modeling and prediction	20000606 703/14

US 6064743 A	Watetable audio synthesizer with waveform volume control for eliminating zipper noise	20000516 381/104
US 6058066 A	Enhanced register array accessible by both a system microprocessor and a wavetable audio :	20000502 365/230.05
US 6052316 A	Output buffer circuitry for semiconductor integrated circuit device	2000418 365/189.05
US 6047073 A	Digital wavetable audio synthesizer with delay-based effects processing	2000404 381/61
US 6041169 A	Method and apparatus for performing integrated circuit timing including noise coupled noise estimation method for on-chip interconnects	20000321 716/6
US 6029117 A	RF amplifier, RF mixer and RF receiver	2000222 702/58
US 6026286 A	High frequency noise and impedance matched integrated circuits	20000215 455/327
US 6002860 A	High-speed logarithmic photo-detector	19991214 703/14
US 6002122 A	Mirror model for designing a continuous-time filter with reduced filter noise	19991214 250/207
US 5926060 A	Audio processing chip with external serial port	19990720 327/538
US 5809466 A	Apparatus and methods for smoothing images	19980915 704/258
US 5799111 A	High frequency noise and impedance matched integrated circuits	19980825 382/254
US 5789799 A	High speed, low noise output buffer	19980804 257/578
US 5760634 A	Watetable audio synthesizer with waveform volume control for eliminating zipper noise	19980602 327/391
US 5742695 A	Motor with variable edge steepness	19980421 381/104
US 5731674 A	Police traffic radar using FFT processing to find fastest target	19980324 318/439
US 5691724 A	Simulation of noise behavior of non-linear circuit	19971125 342/104
US 5682336 A	Power control of circuit modules within an integrated circuit	19971028 703/3
US 5675808 A	Noise generator for evaluating mixed signal integrated circuits	19971007 713/322
US 5668507 A	Watetable audio synthesizer with low frequency oscillators for tremolo and vibrato effects	19970916 33/78
US 5668338 A	Monolithic PC audio circuit with enhanced digital wavetable audio synthesizer	19970916 84/629
US 5659466 A	Police traffic radar using absolute signal strength information to improve target signal process	19961029 342/104
US 5570093 A	Modelling and estimating crosstalk noise and detecting false logic	19961022 716/4
US 5568395 A	Police traffic radar for allowing manual rejection of incorrect patrol speed display	19961015 342/176
US 5565871 A	Police traffic radar using digital data transfer between antenna and counting unit	19961008 342/115
US 5563603 A	Police traffic radar using double balanced mixer for even order harmonic suppression	19960618 342/104
US 5528245 A	Police traffic radar for calculating and simultaneously displaying fastest target speed	19960611 342/104
US 5525996 A	Method and structure for reducing noise in output buffer circuits	19960514 326/127
US 5517130 A	Mixed mode simulation method and simulator	1996102 703/14
US 5481484 A	Logging system for measuring dielectric properties of fluids in a cased well using multiple min	19950926 324/324
US 5453693 A	Serial clock noise immunity in a semiconductor memory integrated circuit having a serial port	19931228 365/189.05
US 5274591 A	Circuit for eliminating digital noise or short pulses utilizing set/reset shift register	19920929 327/34
US 5151612 A	Frequency division network having low phase noise	19920225 327/117
US 5091699 A	Common bus multinode sensor system	19920128 370/482
US 5084868 A	High frequency noise bypassing	19910625 333/12
US 5027089 A	Apparatus and methods for the selective addition of noise to templates employed in automatic	19900612 704/233
US 4933973 A	Wireless remote speaker system	19890711 381/3
US 4847903 A	Instantaneous incremental compiler for producing logic circuit designs	19890502 703/14
US 4827427 A	Common bus multinode sensor system	19880913 376/216
US 4770842 A	Echo canceller with adaptive residual center clipper controlled by echo estimate	19880318 379/406.08
US 4416024 A	Distortion reducing circuit in FM receiver	19831115 455/303
US 3911296 A	Capacitance multiplier circuit	19751007 327/552

**US 6523149 B**  
**US 6327542 B**  
**US 6117182 A**

Noise analysis method for electrical circuit, involves partitioning original multi-port circuit into  
Node coupling voltage noise approximation method for evaluating netlist file uses resistance,  
Noise-reducing buffer insertion method for integrated circuit, involves modeling a data represent

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